

MOS FIELD EFFECT TRANSISTOR μ PA1820

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1820 is a switching device which can be driven directly by a 2.5 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as DC/DC Converters and power management of notebook computers and so on.

FEATURES

- 2.5 V drive available
- · Low on-state resistance

R_{DS(on)1} = 8.6 mΩ MAX. (V_{GS} = 4.5 V, I_D = 6.0 A) R_{DS(on)2} = 8.8 mΩ MAX. (V_{GS} = 4.0 V, I_D = 6.0 A)

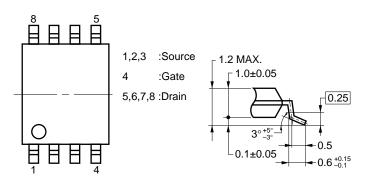
 $R_{\text{DS(on)3}}$ = 12 $m\Omega$ MAX. (Vgs = 2.5 V, Ip = 6.0 A)

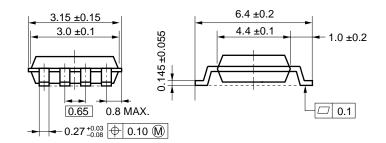
· Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1820GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit: mm)

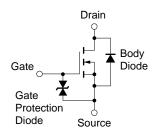




ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	20	V	
Gate to Source Voltage (Vps = 0 V)	Vgss	±12	V	
Drain Current (DC)	ID(DC)	±12	Α	
Drain Current (pulse) Note1	D(pulse)	±48	Α	
Total Power Dissipation Note2	PT	2.0	W	
Channel Temperature	Tch	150	°C	
Storage Temperature	Tstg	-55 to +150	°C	

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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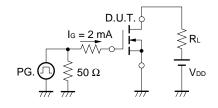
ELECTRICAL CHARACTERISTICS (TA = 25°C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = 20 V, V _{GS} = 0 V			1.0	μΑ
Gate Leakage Current	Igss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1.0 mA	0.5	1.0	1.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 6.0 A	11	21.5		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 4.5 V, ID = 6.0 A		6.8	8.6	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 6.0 A		7.0	8.8	mΩ
	RDS(on)3	Vgs = 2.5 V, ID = 6.0 A		8.7	12	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		2020		pF
Output Capacitance	Coss	V _G s = 0 V		600		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		430		pF
Turn-on Delay Time	t _{d(on)}	VDD = 10 V, ID = 6.0 A		18		ns
Rise Time	tr	Vgs = 4.0 V		56		ns
Turn-off Delay Time	t _{d(off)}	R _G = 10 Ω		75		ns
Fall Time	tf			52		ns
Total Gate Charge	Q _G	V _{DD} = 16 V		27		nC
Gate to Source Charge	Qgs	Vgs = 4.0 V		2.6		nC
Gate to Drain Charge	Q _{GD}	ID = 12 A		13		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 12 A, VGS = 0 V		0.81		V
Reverse Recovery Time	trr	IF = 12 A, VGS = 0 V		61		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A / μs		40		nC

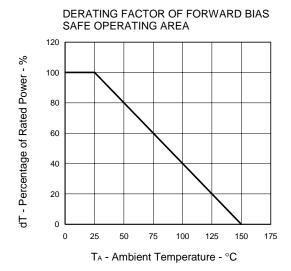
TEST CIRCUIT 1 SWITCHING TIME

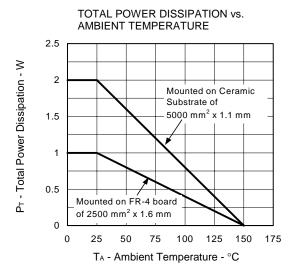
Vgs 90% V_{GS} Wave Form 0 10% Vgs ΙD 90% 90% V_{GS} 0 10% 10% I_D Wave Form $t_{d(on)}$ ton $\tau = 1 \,\mu s$ Duty Cycle ≤ 1%

TEST CIRCUIT 2 GATE CHARGE

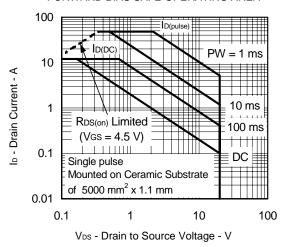


TYPICAL CHARACTERISTICS (TA = 25°C)

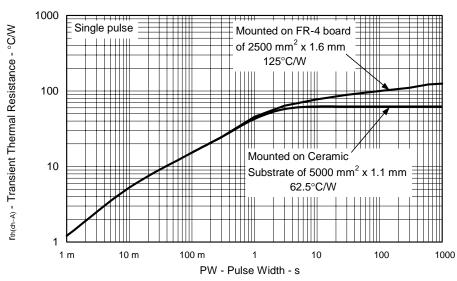




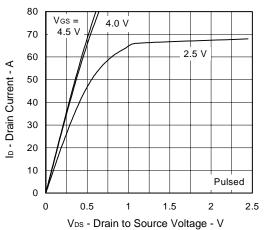
FORWARD BIAS SAFE OPERATING AREA



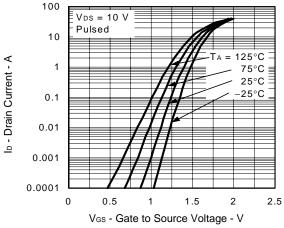
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



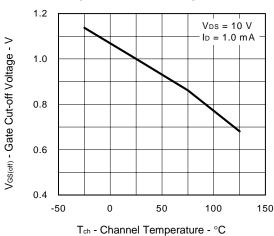
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



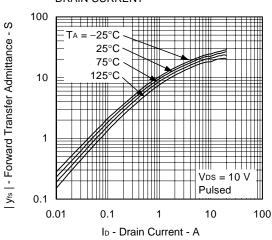
FORWARD TRANSFER CHARACTERISTICS



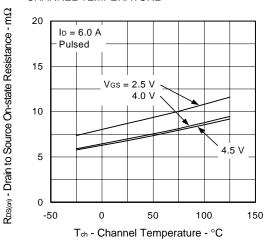
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



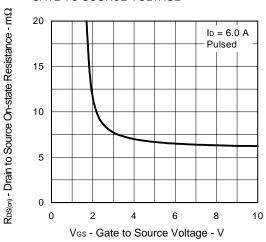
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



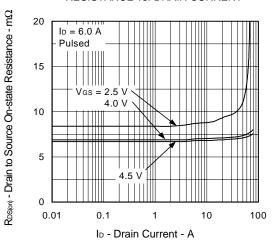
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



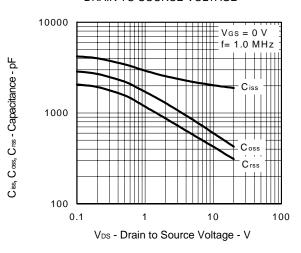
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



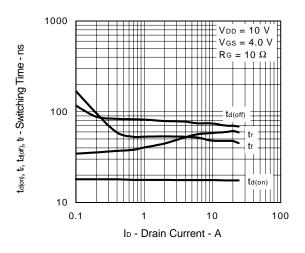
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



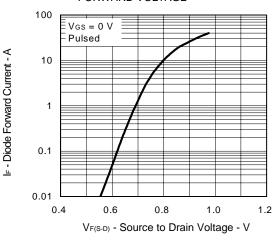
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



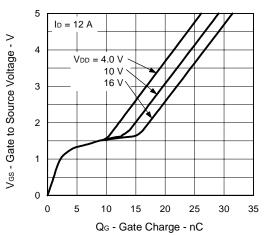
SWITCHING CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



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